DATE: September 15, 1995 PPM-95-178

TO: S. Hull/311.1 FROM: K. Sahu/300.1

SUBJECT: Radiation Report on HST/STIS

Part No. AD829SQ Control No. 12887

cc: A. Sharma/311.0

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A radiation evaluation was performed on AD829 (Op-Amp) to determine the total dose tolerance of these parts. A brief summary of the test results is provided below. For detailed information, refer to Tables I through III.

The total dose testing was performed using a Co<sup>60</sup> gamma ray source. During the radiation testing, five parts were irradiated under bias, and two parts were used as control samples. The total dose radiation levels were 1, 2, 3, and 10 krads\*. The dose rate was between 0.05 and 0.35 krads/hour, depending on the total dose level (see Table II for radiation schedule). After each radiation exposure parts were electrically tested according to the test conditions and the specification limits\*\*.

All parts passed initial electrical measurements. All irradiated parts passed all parametric tests throughout all irradiation steps with no observable radiation-induced effects.

Table III provides a summary of the mean and standard deviation values for each parameter after different irradiation exposures and annealing step.

Any further details about this evaluation can be obtained upon request. If you have any questions, please call me at (301) 731-8954.

<sup>\*</sup>The term rads, as used in this document, means rads(silicon). All radiation levels cited are cumulative.

<sup>\*\*</sup>These are manufacturer's pre-irradiation data specification limits. No post-irradiation limits were provided by the manufacturer at the time these tests were performed.

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#### TABLE I. Part Information

Generic Part Number: AD829

HST/STIS

Part Number: AD829SQ/883B

HST/STIS

Control Number: 12887

Charge Number: EE56352

Manufacturer: Analog Devices Inc

Lot Date Code: 9443A

Quantity Tested: 7

Serial Number of

Control Samples: 60, 61

Serial Numbers of

Radiation Samples: 62, 63, 64, 65, 66

Part Function: Op-Amp

Part Technology: CMOS

Package Style: 8-pin Cerdip

Test Equipment: A540

Test Engineer: Tim Mondy

<sup>\*</sup> No radiation tolerance/hardness was guaranteed by the manufacturer for this part.

## TABLE II. Radiation Schedule for AD829

EVENTS	DATE
1) INITIAL ELECTRICAL MEASUREMENTS	08/07/95
2) 1 KRAD IRRADIATION (0.05 KRADS/HOUR)	08/17/95
POST-1 KRAD ELECTRICAL MEASUREMENT	08/18/95
3) 2 KRAD IRRADIATION (0.05 KRADS/HOUR)	08/18/95
POST-2 KRAD ELECTRICAL MEASUREMENT	08/21/95
4) 3 KRAD IRRADIATION (0.05 KRADS/HOUR)	08/21/95
POST-3 KRAD ELECTRICAL MEASUREMENT	08/22/95
5) 10 KRAD IRRADIATION (0.35 KRADS/HOUR)	08/22/95
POST-10 KRAD ELECTRICAL MEASUREMENT	08/23/95

# Table III: Summary of Electrical Measurements after Total Dose Exposures and Annealing for AD829 /1

							Total dose Exposure (krads)							
					Ini	tial	1		2		3		10	
Test	t Spec. Lim./2													
#	Parameters	Units	min	max	mean	sd	mean	sd	mean	sd	mean	sd	mean	sd
1	Plus_Icc_15V	mA	0	6.8	5.44	0.07	5.51	0.09	5.48	0.09	5.42	0.07	5.49	0.10
2	Minus_Icc_15V	mA	-6.8	0	-5.45	0.08	-5.51	0.09	-5.49	0.09	-5.42	0.07	-5,51	0.10
3	Plus_Icc_5V	mA	0	6.5	5.35	0.07	5.41	0.08	5.39	0.08	5.33	0.07	5.39	0.09
4	Minus_Icc_5V	mA	-6.5	0	-5.35	0.07	-5.41	0.08	-5.39	0.08	-5.33	0.07	-5.40	0.09
5	I_VOS @ 5V	uV	-500	500	48	14	46	12	46	13	44	13	35	13
6	P_IIB @ 5V	uA	-7	7	3	0.21	3	0.19	3	0.18	3	0.19	4	0.15
7	N_IIB @ 5V	uA	-7	7	3	0.21	3	0.19	3	0.19	3	0.19	4	0.15
8	I_IOS @ 5V	nA	-500	500	-2,63	5.37	-1.79	4.91	0.71	5.75	1,24	6.60	19.2	15.5
9	I_VOS @ 15V	uV	-500	500	71	18	71	18	66	19	62	18	-13	24
10	P_IIB @ 15V	uA	-7	7	3	0.2	3	0.18	3	0.18	3	0.18	3	0.14
11	N_IIB @ 15V	uA	-7	7	3	0.2	3	0.19	3	0.18	3	0.18	3	0.15
12	I_IOS @ 15V	nA	-500	500	1.57	5.15	2,42	5.75	4.54	5.63	5,59	6.78	28.1	16.1
13	+CMRR_1	dB	100	-	119	5.9	119	6.08	130	23	129	21	121	7.93
14	-CMRR_1	dB	100	-	122	6.65	121	6.53	123	7.85	123	7.43	120	5.59
15	+CMRR_2	dB	100	-	127	16.4	121	8.03	127	11.8	126	10.7	127	13.6
16	-CMRR_2	dB	100	-	113	4.41	115	4.69	123	6.95	123	7.06	123	6.62
17	PSRR	dB	98	-	118	2.11	118	2.15	119	2.41	120	2.43	106	2.27
18	P_VOUT @ 12mA	$\mathbf{V}$	12	-	14.3	0.02	14.1	0.02	13.9	0.01	13.9	0.01	13.9	0.01
19	P_VOUT @ 20mA	$\mathbf{V}$	10	-	14.1	0.02	14.0	0.02	13.6	0.02	13.6	0.02	13.6	0.01
20	N_VOUT @ 12mA	$\mathbf{v}$	-	-12	-13.6	0.01	-13.6	0.0	-13.6	0.0	-13.6	0.01	-13.6	0.0
21	N_VOUT @ 20mA	$\mathbf{V}$	-	-10	-13.4	0.01	-13.4	0.01	-13.4	0.01	-13.4	0.01	-13.4	0.01
22	P_VOUT @ 6mA	$\mathbf{v}$	3	-	3.51	0.01	3.65	0.01	4.04	0.01	4.04	0.0	4.04	0.01
23	P_VOUT @ 16mA	$\mathbf{V}$	2.5	-	3.29	0.01	3,49	0.01	3.74	0.01	3.74	0.01	3.73	0.01
24	N_VOUT @ 6mA	$\mathbf{V}$	-	-3	-3.83	0.0	-3.83	0.0	-3.83	0.0	-3.83	0.0	-3.83	0.0
25	N_VOUT @ 16mA	$\mathbf{v}$	-	-2.5	-3.53	0.0	-3.53	0.01	-3.52	0.01	-3.53	0.01	-3.53	0.0
26	P_AOL V/mV @ 10mV	V/mV	50	-	103	5.07	103	4.77	101	4.61	100	4.72	98.1	4.56
27	V_AOL V/mV @ 10mV	V/mV	50	-	111	5.17	111	5.08	110	4.98	109	4.93	106	4.94
28	P_AOL V/mV @ 5mV	V/mV	30	-	59.1	1.39	61.9	1.31	62.9	1.51	62.1	1.41	59.6	1.23
29	V_AOL V/mV @ 5mV	V/mV	30	-	69.7	4.22	70.2	4.45	70.2	4.34	69.1	4.20	65.9	3.87
30	VNoise	nV			2.34	0.08	2.33	0.07	2.43	0.09	2.39	0.11	2.42	0.88
31	INoise	fA			68	0.75	69	0.69	69	0.71	68	0.79	67	0.81
32	Slew Rate	V/uS			164	3.61	162	3.32	162	3.51	165	4.01	162	3.41
33	GBW	MHz			719	15.2	728	11.2	722	9.27	725	12.2	727	10.9
34	Settling	nS			80	0.0	80	0.0	80	0.0	80	0.0	80	0.0

# Notes:

- 1/ The mean and standard deviation values were calculated over the five parts irradiated in this testing. The control samples remained constant throughout the testing and are not included in this table.
- 2/ These are manufacturer's pre-irradiation data sheet specification limits.